

| L Number | Hits | Search Text | DB | Time stamp |
|----------|------|--|----------|------------|
| 1 | 3 | 4761607.pn. or 4357540.pn. or 4503329.pn. | USPAT; | 2004/04/26 |
| 2 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (until near3 failure) | US-PGPUB | 16:39 |
| 3 | 1 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and failure\$2 | USPAT; | 2004/04/26 |
| 4 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with induce\$2) | US-PGPUB | 16:19 |
| 5 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with (induc\$5 or introduc\$5)) | USPAT; | 2004/04/26 |
| 6 | 56 | (inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5)) | US-PGPUB | 16:06 |
| 7 | 15 | (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)) | USPAT; | 2004/04/26 |
| 8 | 11 | (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5) | US-PGPUB | 16:33 |
| 9 | 1 | ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)) and ((scanning adj electron adj microscop\$5) or SEM) | USPAT; | 2004/04/26 |
| 11 | 0 | 5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)) | US-PGPUB | 16:11 |
| 12 | 0 | 5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5) | USPAT; | 2004/04/26 |
| 13 | 0 | 5475695.pn. and (failure\$2 with induc\$5) | US-PGPUB | 16:18 |
| 14 | 0 | 5475695.pn. and (until near3 failure) | USPAT; | 2004/04/26 |
| 15 | 1 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (until near3 failure) | US-PGPUB | 16:31 |
| 17 | 11 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5) | USPAT; | 2004/04/26 |
| 18 | 15 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)) | US-PGPUB | 16:32 |
| 19 | 15 | ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))) not (5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))) | USPAT; | 2004/04/26 |
| 20 | 4 | ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))) not ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)) | US-PGPUB | 16:33 |

| | | | | |
|----|----|---|--------------------|---------------------|
| 16 | 43 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:37 |
| 21 | 0 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5 with (maximum near3 rating)) | USPAT; US-PGPUB | 2004/04/26 16:38 |
| 22 | 0 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with (maximum near3 rating)) | USPAT; US-PGPUB | 2004/04/26 16:38 |
| 23 | 0 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and failure\$2 and (maximum near3 rating) | USPAT; US-PGPUB | 2004/04/26 16:39 |
| 24 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:39 |
| 25 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (fail\$7 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:40 |
| 26 | 43 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (fail\$7 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:40 |
| 27 | 19 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (fail\$7 near5 induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:40 |
| 10 | 1 | 5475695.pn. | USPAT; US-PGPUB | 2004/04/26 17:07 |
| 28 | 0 | 5475695.pn. and (SEM) | USPAT; US-PGPUB | 2004/04/26 17:08 |
| 29 | 0 | 5475695.pn. and (scanning adj electron adj microscop\$3) | USPAT; US-PGPUB | 2004/04/26 17:08 |
| 30 | 3 | 5475695.pn. or 6320396.pn. or 5523694.pn. | USPAT; US-PGPUB | 2004/04/26 17:09 |
| 31 | 1 | (5475695.pn. or 6320396.pn. or 5523694.pn.) and DUT | USPAT; US-PGPUB | 2004/04/26 17:09 |
| 32 | 1 | ((5475695.pn. or 6320396.pn. or 5523694.pn.) and DUT) and (induc\$4 near3 (fault\$3 or defect\$3)) | USPAT; US-PGPUB | 2004/04/26 17:12 |
| 33 | 1 | (5475695.pn. or 6320396.pn. or 5523694.pn.) and (image with subtract\$5) | USPAT; US-PGPUB | 2004/04/26 17:15 |
| 34 | 60 | (5475695.pn. or 6320396.pn. or 5523694.pn.) or (4761607.pn. or 4357540.pn. or 4503329.pn.) or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or 5475695.pn. and (continuous near3 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:18 |
| 35 | 0 | ((5475695.pn. or 6320396.pn. or 5523694.pn.) and DUT) and (continuous near3 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:16 |
| 36 | 0 | (5475695.pn. or 6320396.pn. or 5523694.pn.) and (continuous near3 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:16 |
| 37 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (continuous near3 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:17 |
| 38 | 0 | ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)) and (continuous near3 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:17 |
| 39 | 0 | (5475695.pn. or 6320396.pn. or 5523694.pn.) and (continuous near3 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:17 |

| | | | | |
|----|----|---|--------------------|---------------------|
| 40 | 0 | 5475695.pn. and (continuous near3 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:17 |
| 41 | 0 | ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)) and (continuous near3 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:18 |
| 42 | 0 | ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) and (continuous near3 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:18 |
| 43 | 0 | ((5475695.pn. or 6320396.pn. or 5523694.pn.) or (4761607.pn. or 4357540.pn. or 4503329.pn.) or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or 5475695.pn.) and (continuous near3 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:18 |
| 44 | 0 | ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) and (continuous adj loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:19 |
| 45 | 0 | (5475695.pn. or 6320396.pn. or 5523694.pn.) and (continuous adj loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:19 |
| 46 | 0 | (5475695.pn. or 6320396.pn. or 5523694.pn.) and (feedback adj loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:19 |
| 47 | 0 | 5475695.pn. and (feedback adj loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:19 |
| 48 | 0 | 5475695.pn. and (automatic near4 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:20 |
| 49 | 0 | 5475695.pn. and (automat\$4 near4 loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:20 |
| 50 | 1 | 5475695.pn. and (automat\$4) | USPAT; US-PGPUB | 2004/04/26 17:20 |
| 51 | 0 | 5475695.pn. and (automat\$4 with feedback\$2) | USPAT; US-PGPUB | 2004/04/26 17:21 |
| 52 | 0 | ((5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5)) and (automat\$4 with feedback\$2) | USPAT; US-PGPUB | 2004/04/26 17:21 |
| 54 | 0 | ((5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5)) and ((automat\$4 or feedback\$2) with loop\$3) | USPAT; US-PGPUB | 2004/04/26 17:21 |
| 53 | 24 | ((5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5)) and (automat\$4 or feedback\$2) | USPAT; US-PGPUB | 2004/04/26 17:21 |
| 55 | 1 | 6344750.pn. | USPAT; US-PGPUB | 2004/04/26 18:31 |
| 56 | 1 | 20020043628.pn. | USPAT; US-PGPUB | 2004/04/26 18:31 |

| | Type | L # | Hits | Search Text | DBs | Time Stamp | Comments |
|----|------|-----|------|--|----------------------------|----------------------|----------|
| 1 | BRS | L1 | 3 | 4761607.pn. or 4357540.pn. or 4503329.pn. | USPA T; US-P GPUB | 2004/04/2 6 16:39 | |
| 2 | BRS | L2 | 0 | L1 and (until near3 failure) | USPA T; US-P GPUB | 2004/04/2 6 16:19 | |
| 3 | BRS | L3 | 1 | L1 and failure\$2 | USPA T; US-P GPUB | 2004/04/2 6 16:06 | |
| 4 | BRS | L4 | 0 | L1 and (failure\$2 with induce\$2) | USPA T; US-P GPUB | 2004/04/2 6 16:07 | |
| 5 | BRS | L5 | 0 | L1 and (failure\$2 with (induc\$5 or introduc\$5)) | USPA T; US-P GPUB | 2004/04/2 6 16:39 | |
| 6 | BRS | L6 | 56 | (inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5)) | USPA T; US-P GPUB | 2004/04/2 6 16:08 | |
| 7 | BRS | L7 | 15 | (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)) | USPA T; US-P GPUB | 2004/04/2 6 16:33 | |
| 8 | BRS | L8 | 11 | (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5) | USPA T; US-P GPUB | 2004/04/2 6 16:32 | |
| 9 | BRS | L9 | 1 | L8 and ((scanning adj electron adj microscop\$5) or SEM) | USPA T; US-P GPUB | 2004/04/2 6 16:11 | |
| 10 | BRS | L10 | 1 | 5475695.pn. | USPA T; US-P GPUB | 2004/04/2 6 16:17 | |
| 11 | BRS | L11 | 0 | L10 and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)) | USPA T; US-P GPUB | 2004/04/2 6 16:18 | |

| | Error Definition | Er ro rs |
|----|---------------------|----------------|
| 1 | | 0 |
| 2 | | 0 |
| 3 | | 0 |
| 4 | | 0 |
| 5 | | 0 |
| 6 | | 0 |
| 7 | | 0 |
| 8 | | 0 |
| 9 | | 0 |
| 10 | | 0 |
| 11 | | 0 |

| | Type | L # | Hits | Search T xt | DBs | Time Stamp | Comments |
|----|------|-----|------|--|----------------------------|------------------|----------|
| 12 | BRS | L12 | 0 | L10 and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5) | USPA T; US-P GPUB | 2004/04/26 16:18 | |
| 13 | BRS | L13 | 0 | L10 and (failure\$2 with induc\$5) | USPA T; US-P GPUB | 2004/04/26 16:31 | |
| 14 | BRS | L14 | 0 | L10 and (until near3 failure) | USPA T; US-P GPUB | 2004/04/26 16:30 | |
| 15 | BRS | L15 | 1 | (L10 or L6 or L1) and (until near3 failure) | USPA T; US-P GPUB | 2004/04/26 16:30 | |
| 16 | BRS | L17 | 11 | (L10 or L6 or L1) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5) | USPA T; US-P GPUB | 2004/04/26 16:32 | |
| 17 | BRS | L18 | 15 | (L10 or L6 or L1) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)) | USPA T; US-P GPUB | 2004/04/26 16:32 | |
| 18 | BRS | L19 | 15 | L7 not L11 | USPA T; US-P GPUB | 2004/04/26 16:33 | |
| 19 | BRS | L20 | 4 | L7 not L8 | USPA T; US-P GPUB | 2004/04/26 16:33 | |
| 20 | BRS | L16 | 43 | (L10 or L6 or L1) and (failure\$2 with induc\$5) | USPA T; US-P GPUB | 2004/04/26 16:37 | |
| 21 | BRS | L21 | 0 | (L10 or L6 or L1) and (failure\$2 with induc\$5 with (maximum near3 rating)) | USPA T; US-P GPUB | 2004/04/26 16:38 | |
| 22 | BRS | L22 | 0 | (L10 or L6 or L1) and (failure\$2 with (maximum near3 rating)) | USPA T; US-P GPUB | 2004/04/26 16:38 | |

| | Error Definition | Er ro rs |
|----|---------------------|----------------|
| 12 | | 0 |
| 13 | | 0 |
| 14 | | 0 |
| 15 | | 0 |
| 16 | | 0 |
| 17 | | 0 |
| 18 | | 0 |
| 19 | | 0 |
| 20 | | 0 |
| 21 | | 0 |
| 22 | | 0 |

| | Type | L # | Hits | Search Text | DBs | Time Stamp | Comments |
|----|------|-----|------|---|----------------------------|------------------|----------|
| 23 | BRS | L23 | 0 | (L10 or L6 or L1) and failure\$2 and (maximum near3 rating) | USPA T; US-P GPUB | 2004/04/26 16:39 | |
| 24 | BRS | L24 | 0 | L1 and (failure\$2 with induc\$5) | USPA T; US-P GPUB | 2004/04/26 16:39 | |
| 25 | BRS | L25 | 0 | L1 and (fail\$7 with induc\$5) | USPA T; US-P GPUB | 2004/04/26 16:40 | |
| 26 | BRS | L26 | 43 | (L10 or L6 or L1) and (fail\$7 with induc\$5) | USPA T; US-P GPUB | 2004/04/26 16:40 | |
| 27 | BRS | L27 | 19 | (L10 or L6 or L1) and (fail\$7 near5 induc\$5) | USPA T; US-P GPUB | 2004/04/26 16:40 | |

| | Error Definition | Er ro rs |
|----|---------------------|----------------|
| 23 | | 0 |
| 24 | | 0 |
| 25 | | 0 |
| 26 | | 0 |
| 27 | | 0 |

| L Number | Hits | Search Text | DB | Time stamp |
|----------|------|--|--------------------|---------------------|
| 1 | 3 | 4761607.pn. or 4357540.pn. or 4503329.pn. | USPAT; US-PGPUB | 2004/04/26 16:39 |
| 2 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (until near3 failure) | USPAT; US-PGPUB | 2004/04/26 16:19 |
| 3 | 1 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and failure\$2 | USPAT; US-PGPUB | 2004/04/26 16:06 |
| 4 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with induce\$2) | USPAT; US-PGPUB | 2004/04/26 16:07 |
| 5 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with (induc\$5 or introduc\$5)) | USPAT; US-PGPUB | 2004/04/26 16:39 |
| 6 | 56 | (inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5)) | USPAT; US-PGPUB | 2004/04/26 16:08 |
| 7 | 15 | (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)) | USPAT; US-PGPUB | 2004/04/26 16:33 |
| 8 | 11 | (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:32 |
| 9 | 1 | ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)) and ((scanning adj electron adj microscop\$5) or SEM) | USPAT; US-PGPUB | 2004/04/26 16:11 |
| 10 | 1 | 5475695.pn. | USPAT; US-PGPUB | 2004/04/26 16:17 |
| 11 | 0 | 5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)) | USPAT; US-PGPUB | 2004/04/26 16:18 |
| 12 | 0 | 5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:18 |
| 13 | 0 | 5475695.pn. and (failure\$2 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:31 |
| 14 | 0 | 5475695.pn. and (until near3 failure) | USPAT; US-PGPUB | 2004/04/26 16:30 |
| 15 | 1 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (until near3 failure) | USPAT; US-PGPUB | 2004/04/26 16:30 |
| 17 | 11 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:32 |
| 18 | 15 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5)) | USPAT; US-PGPUB | 2004/04/26 16:32 |
| 19 | 15 | ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))) not (5475695.pn. and (inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))) | USPAT; US-PGPUB | 2004/04/26 16:33 |
| 20 | 4 | ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with (induc\$5 or introduc\$5))) not ((inspect\$5 with (semiconduct\$5 near3 (die\$2 or chip\$2))) and (failure\$2 with induc\$5)) | USPAT; US-PGPUB | 2004/04/26 16:33 |

| | | | | |
|----|----|--|--------------------|---------------------|
| 16 | 43 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:37 |
| 21 | 0 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with induc\$5 with (maximum near3 rating)) | USPAT; US-PGPUB | 2004/04/26 16:38 |
| 22 | 0 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (failure\$2 with (maximum near3 rating)) | USPAT; US-PGPUB | 2004/04/26 16:38 |
| 23 | 0 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and failure\$2 and (maximum near3 rating) | USPAT; US-PGPUB | 2004/04/26 16:39 |
| 24 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (failure\$2 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:39 |
| 25 | 0 | (4761607.pn. or 4357540.pn. or 4503329.pn.) and (fail\$7 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:40 |
| 26 | 43 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (fail\$7 with induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:40 |
| 27 | 19 | (5475695.pn. or ((inspect\$5 with (die\$2 or chip\$2)) and (failure\$2 with (induc\$5 or introduc\$5))) or (4761607.pn. or 4357540.pn. or 4503329.pn.)) and (fail\$7 near5 induc\$5) | USPAT; US-PGPUB | 2004/04/26 16:40 |